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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No.	
	December 4, 2000
Inventor	Charles H. Dennison
Assignee	Micron Technology, Inc.
Group Art Unit	2811
Examiner	Ori Nadav
Attorney Docket No	MI22-1577
Customer No	
Title	Field Effect Transistors and Integrated Circuitry

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. Copies of the cited art are included. No admission is made regarding whether all the submitted references are prior art.

Respectfully submitted,

Dated: 11-14-03

Mark S. Matkin Reg. No. 32,268

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